

FDS4488

30V N-Channel PowerTrench^O MOSFET

General Description

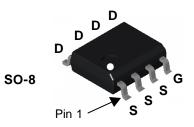
This NChannel MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize on-state resistance and yet maintain superior switching performance. These devices are well suited for low voltage and battery powered applications where low inline power loss and fast switching are required.

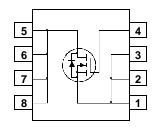
Applications

- DC/DC converter
- Load switch
- Motor drives

Features

- 7.9 A, 30 V. $R_{DS(ON)} = 22 \text{ m}\Omega$ @ $V_{GS} = 10 \text{ V}$ $R_{DS(ON)} = 30 \text{ m}\Omega$ @ $V_{GS} = 4.5 \text{ V}$
- Low gate charge (9.5 nC typical)
- High performance trench technology for extremely low R_{DS(ON)}
- High power and current handling capability





Absolute Maximum Ratings T_A=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-Source Voltage		30	V
V_{GSS}	Gate-Source Voltage		±25	V
l _D	Drain Current - Continuous	(Note 1a)	7.9	Α
	- Pulsed		40	
P _D	Power Dissipation for Single Operation	(Note 1a)	2.5	W
		(Note 1b)	1.2	
		(Note 1c)	1.0	
T_J , T_{STG}	Operating and Storage Junction Temperature Range		-55 to +175	°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	50	°C/W
R ₀ JC	Thermal Resistance, Junction-to-Case	(Note 1)	25	

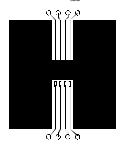
Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
FDS4488	FDS4488	13"	12mm	2500 units

Electric	cal Characteristics	T _A = 25°C unless otherwise noted		_		
Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics			•		
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, \qquad I_D = 250 \mu\text{A}$	30			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu\text{A}$, Referenced to 25°C		21		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 24 \text{ V}, V_{GS} = 0 \text{ V}$			1	μΑ
I _{GSSF}	Gate-Body Leakage, Forward	$V_{GS} = 25 \text{ V}, V_{DS} = 0 \text{ V}$			100	nA
I _{GSSR}	Gate-Body Leakage, Reverse	$V_{GS} = -25 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
On Char	acteristics (Note 2)					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_{D} = 250 \mu\text{A}$	1	1.8	3	V
$\Delta V_{GS(th)} \over \Delta T_J$	Gate Threshold Voltage Temperature Coefficient	$I_D = 250 \mu\text{A}$, Referenced to 25°C		-6		mV/°C
R _{DS(on)}	Static Drain-Source	$V_{GS} = 10 \text{ V}, \qquad I_D = 7.9 \text{ A}$		15	22	mΩ
	On–Resistance	$V_{GS} = 4.5 \text{ V}, I_D = 6.8 \text{ A}$ $V_{GS} = 10 \text{ V}, I_D = 7.9 \text{ A}, T_J = 125 ^{\circ}\text{C}$		21	30	
1	On Otata Busin Occurrent		00	22	35	Δ.
D(on)	On–State Drain Current	V _{GS} = 10 V, V _{DS} = 5 V	20	0.4		A
g FS	Forward Transconductance	$V_{DS} = 10 \text{ V}, \qquad I_D = 7.9 \text{ A}$		24		S
	Characteristics					
C _{iss}	Input Capacitance	$V_{DS} = 15 \text{ V}, \qquad V_{GS} = 0 \text{ V},$		927		pF
Coss	Output Capacitance	f = 1.0 MHz		241		pF
C _{rss}	Reverse Transfer Capacitance			97		pF
Switchin	g Characteristics (Note 2)					
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 15 \text{ V}, I_D = 1 \text{ A},$		7.4	15	ns
t _r	Turn-On Rise Time	$V_{GS} = 10 \text{ V}, R_{GEN} = 6 \Omega$		7.5	15	ns
t _{d(off)}	Turn-Off Delay Time			25	40	ns
t _f	Turn-Off Fall Time			5	10	ns
Qg	Total Gate Charge	$V_{DS} = 15 \text{ V}, \qquad I_D = 7.9 \text{ A},$		9.5	13	nC
Q _{gs}	Gate-Source Charge	$V_{GS} = 5 V$		3.3		nC
Q _{gd}	Gate-Drain Charge			3.1		nC
Drain-So	ource Diode Characteristics	and Maximum Ratings		•		
ls	Maximum Continuous Drain-Source				2.1	Α
V_{SD}	Drain–Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 2.1 \text{ A}$ (Note 2)		0.7	1.2	V
t _{rr}	Diode Reverse Recovery Time	I _F = 7.9 A,		22		nS
Q _{rr}	Diode Reverse Recovery Charge	$d_{iF}/d_t = 100 \text{ A/}\mu\text{s}$		20		nC

Notes

R_{QAR} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of
the drain pins. R_{BAC} is guaranteed by design while R_{BCA} is determined by the user's board design.



a) 50°C/W when mounted on a 1in² pad of 2 oz copper



b) 105°C/W when mounted on a .04 ir² pad of 2 oz copper



c) 125°C/W when mounted on a minimum pad.



Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width < 300 $\mu s,$ Duty Cycle < 2.0%

Typical Characteristics

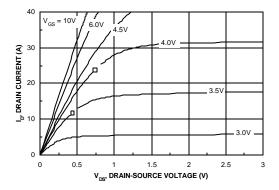


Figure 1. On-Region Characteristics.

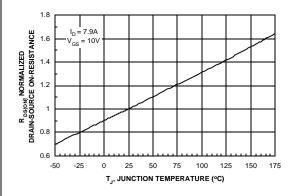


Figure 3. On-Resistance Variation with Temperature.

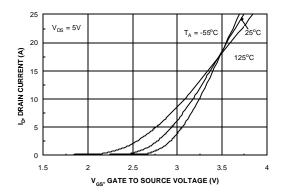


Figure 5. Transfer Characteristics.

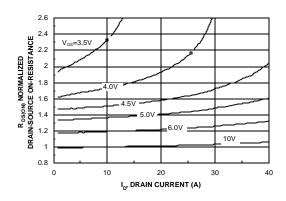


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

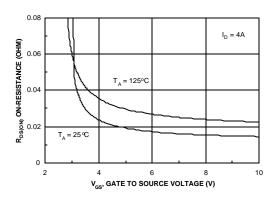


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

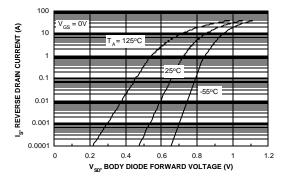
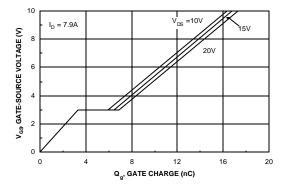


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics



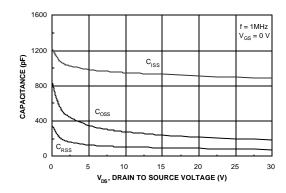


Figure 7. Gate Charge Characteristics.

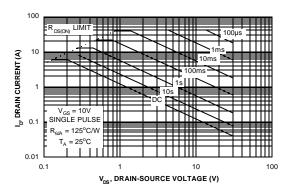


Figure 8. Capacitance Characteristics.

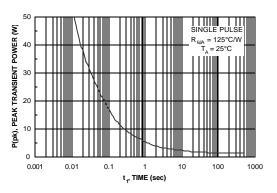


Figure 9. Maximum Safe Operating Area.



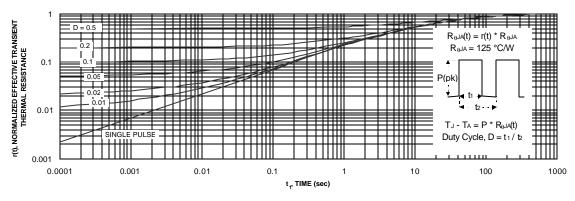


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c. Transient thermal response will change depending on the circuit board design.

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